

**Search Notes**

Application/Control No.

10/633,642

Examiner

Rick K. Chang

Applicant(s)/Patent under  
Reexamination

FURUKAWA ET AL.

Art Unit

3729

**SEARCHED**

Class	Subclass	Date	Examiner
29	610.1,611, 612	9/6/2005	RC
338	195,314		
	225D		
	22R,22SD		

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
east search	9/6/2005	RC